L	Hits	Search Text	DB	Time stamp
Number				
1	3	(grating same interfer\$) same (overlay	USPAT;	2004/08/18
		same latent)	US-PGPUB	17:22
2	10	(grating same interfer\$) and (overlay	USPAT;	2004/08/18
		same latent)	US-PGPUB	17:22
3	101	((356/508,509,496).CCLS.) and ((mask	USPAT	2004/08/18
		reticle photomask reticule) same		17:22
		(substrate wafer semiconduct\$))		
4	117	((356/508,509,496).CCLS.) and ((mask	USPAT;	2004/08/18
		reticle photomask reticule) same	US-PGPUB	17:22
		(substrate wafer semiconduct\$))		
5	343		USPAT;	2004/08/18
		semiconduct\$)) and ((imag\$3 project\$	US-PGPUB	17:23
		expos\$3) same (overlay same (resist		
		photoresist)))		
6	2234	(356/399-401).CCLS.	USPAT;	2004/08/18
			US-PGPUB	17:23
7	3204	(355/53,55).CCLS.	USPAT;	2004/08/18
			US-PGPUB	17:23
8	5370	(430/5,22,30).CCLS.	USPAT;	2004/08/18
			US-PGPUB	17:23
9	996	(250/548).CCLS.	USPAT;	2004/08/18
			US-PGPUB	17:23
10	166	((356/399-401).CCLS.) and (overlay same	USPAT;	2004/08/18
		(grating mark\$ target))	US-PGPUB	17:23
11	123	1 ' -	USPAT;	2004/08/18
		(grating mark\$ target))	US-PGPUB	17:23
12	206	(, , ,	USPAT;	2004/08/18
		(grating mark\$ target))	US-PGPUB	17:23
13	35	(\= , , = - ,	USPAT;	2004/08/18
		(grating mark\$ target))	US-PGPUB	17:24